

# A guide to juggling the AFM in chemistry

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Atomic force microscopy is an extraordinary investigative tool but, at the same time, in some cases a pitfall for us researchers. The correct interpretation of the measurements sometimes involves an accurate knowledge of the investigated system and an appropriate preparation of the sample.

For this reason, the study of molecular complexes or the presence of preparation residues in liquid depositions can make the interpretation of the results problematic.

In this talk I present some situations that have occurred over the years and how one can come to terms with them by understanding how to act on the experimental parameters and how to exploit all the physical information that the AFM can provide.

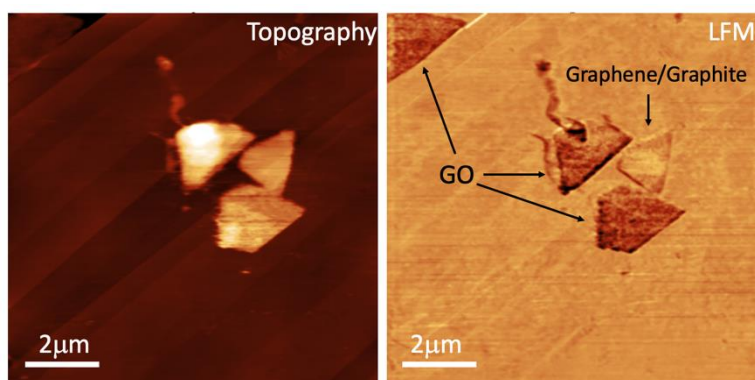


Fig. 1. Example of recognition of graphene oxide (GO) deposited on graphite by lateral force microscopy (LFM).